



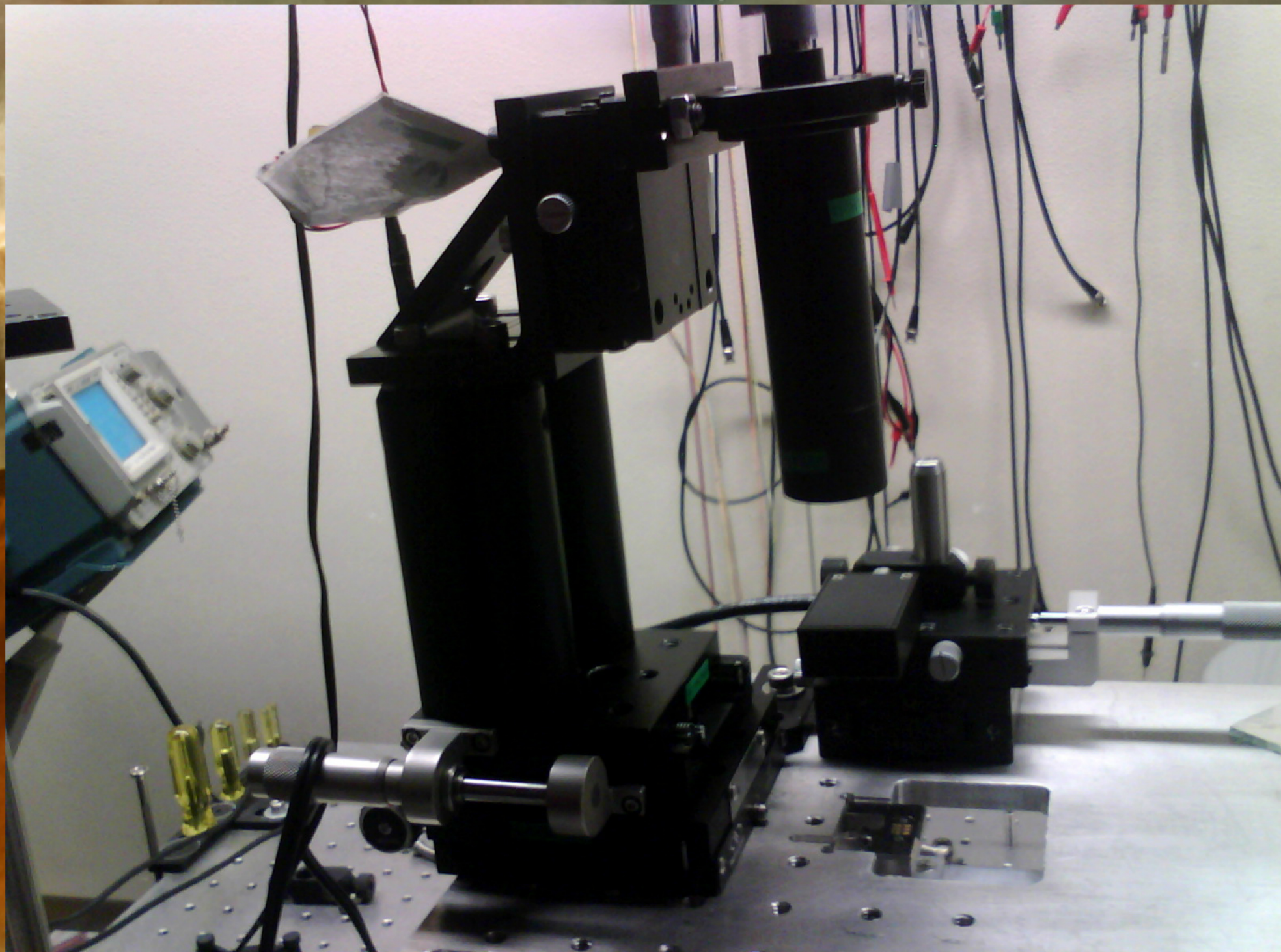
# Atomic Force Microscope





# This Term

- Fixed weird electrical behavior
- Wrote software for new Intermittent Contact Measurement (ICM) method.
- Programmed Data interrupt
- Almost completed a user manual.
- Refocussed and Profiled Laser beam
- Reconfigured setup
- Reconfigured setup
- Reconfigured setup
- Tip stuff





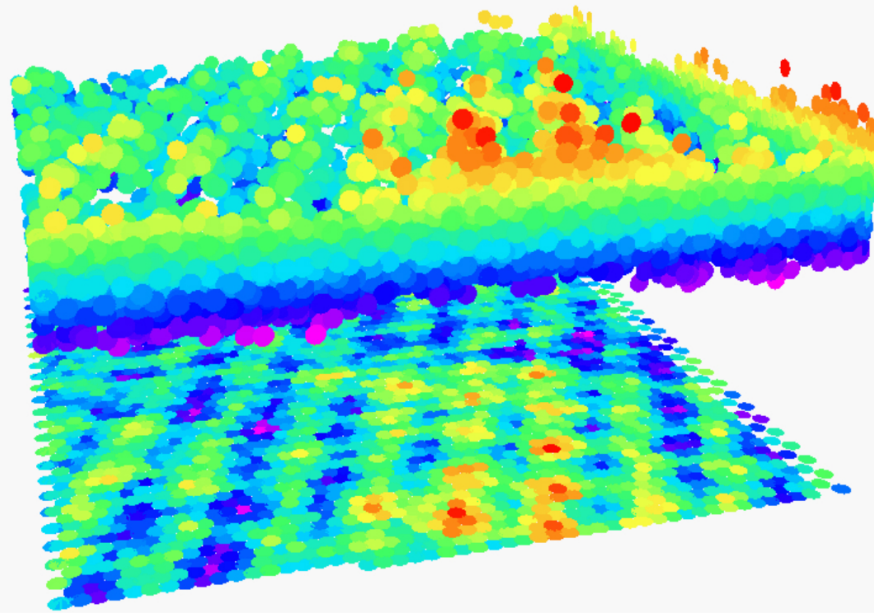


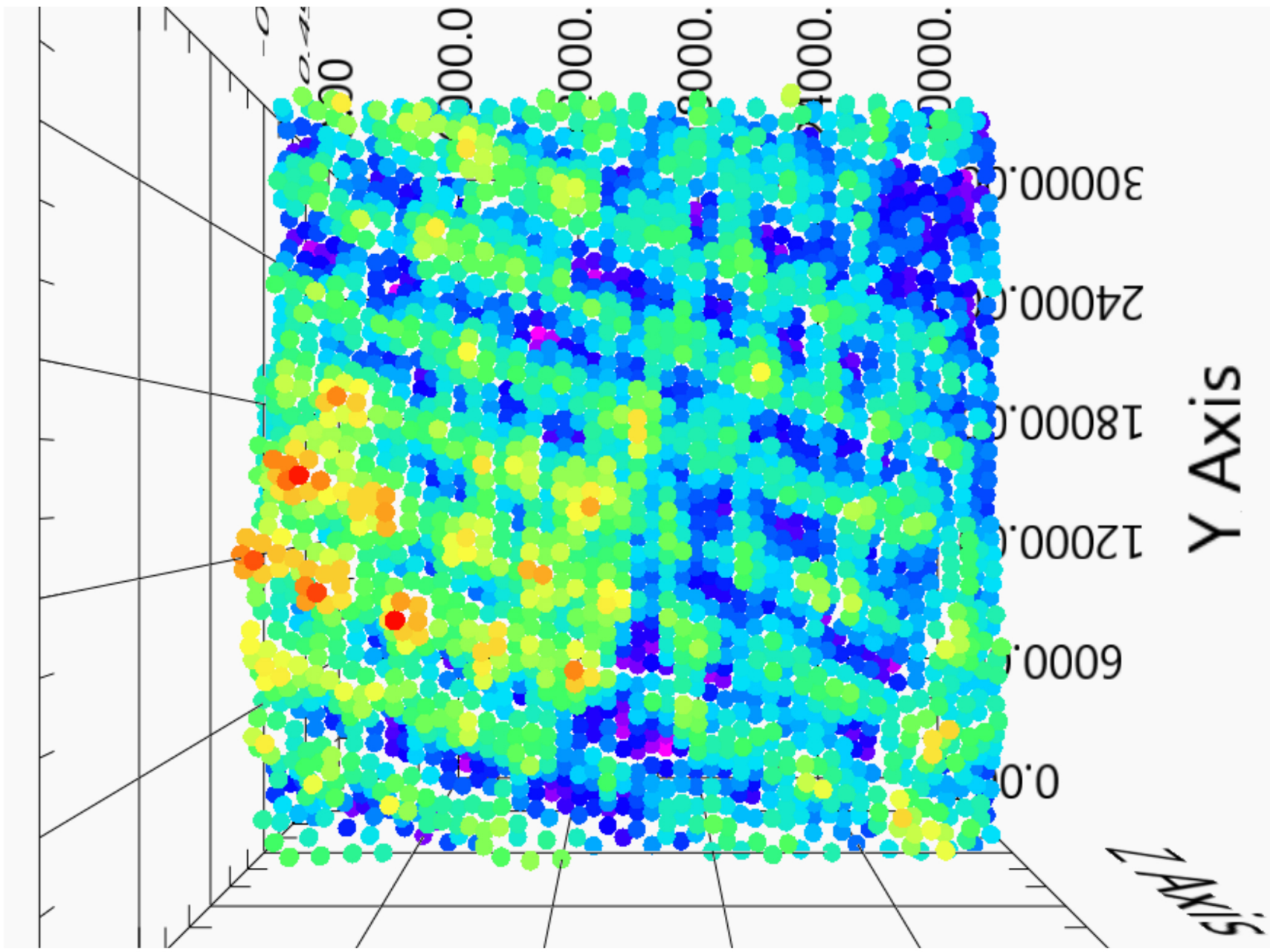






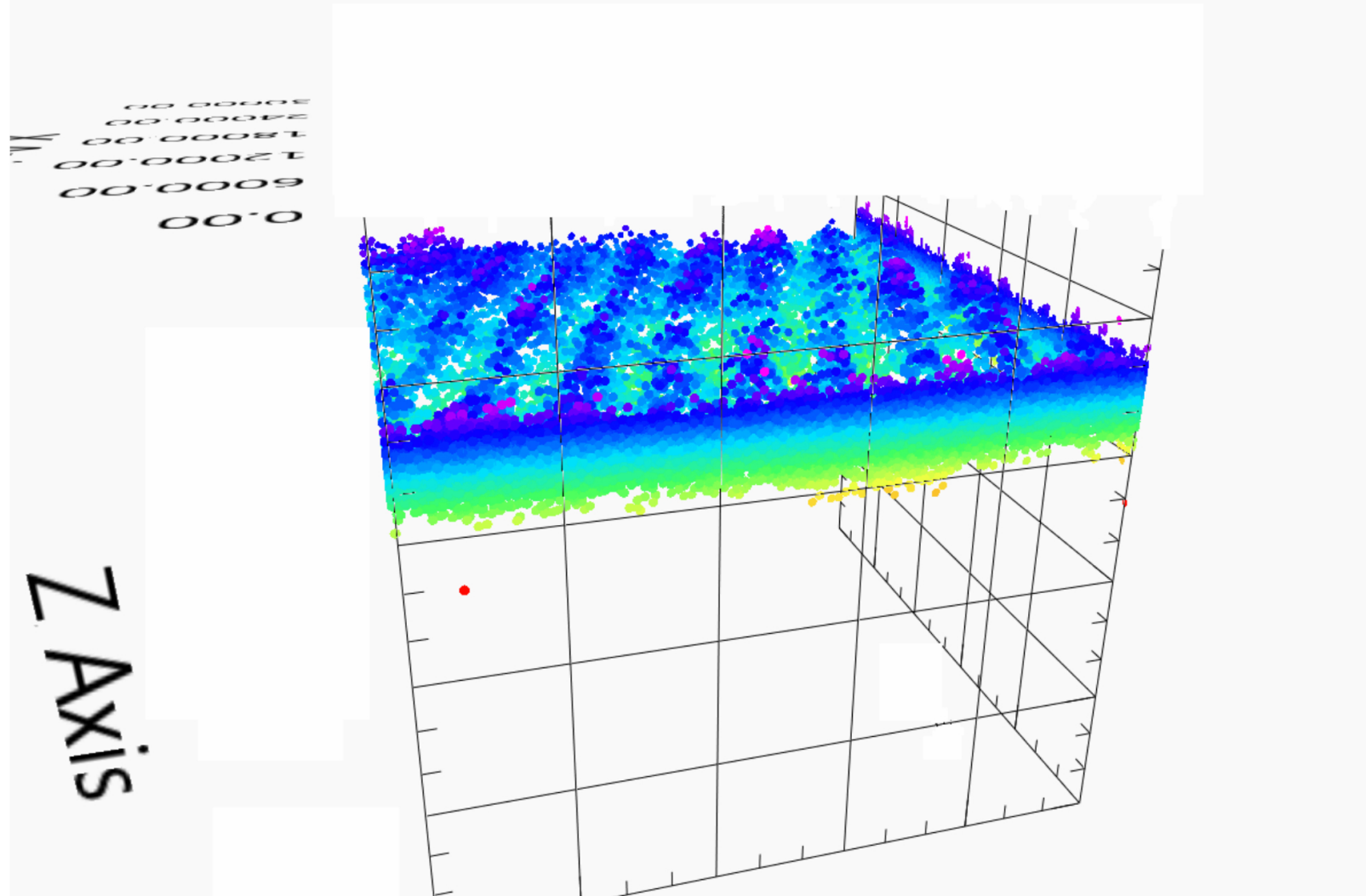
## First Attempt: Sample Stage

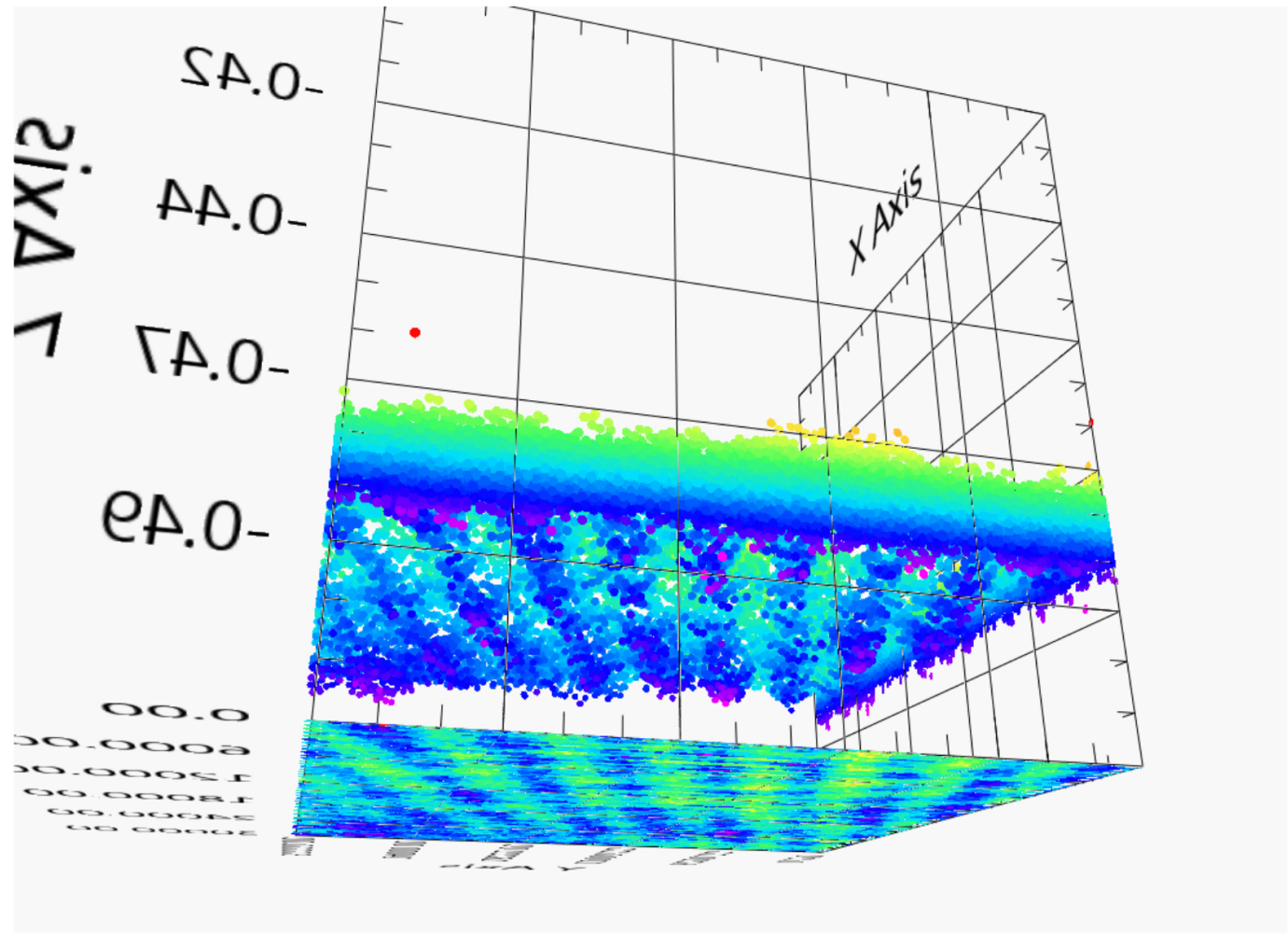






## Second Attempt: Sample Stage

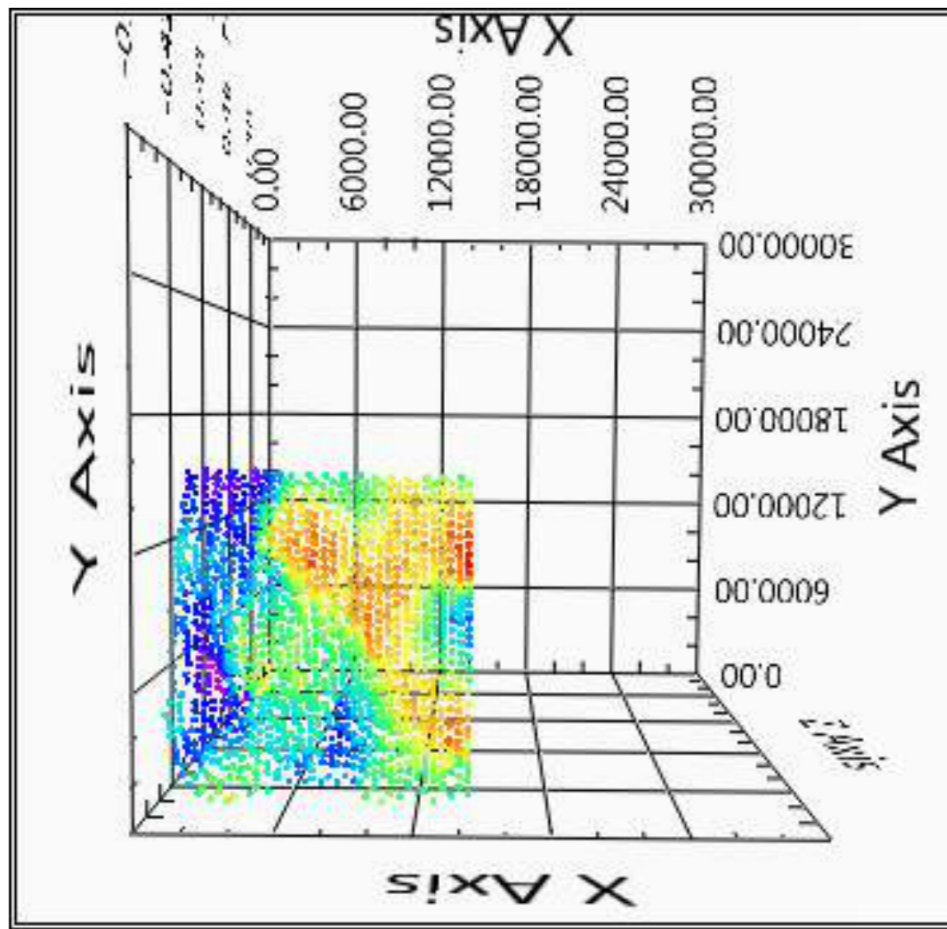
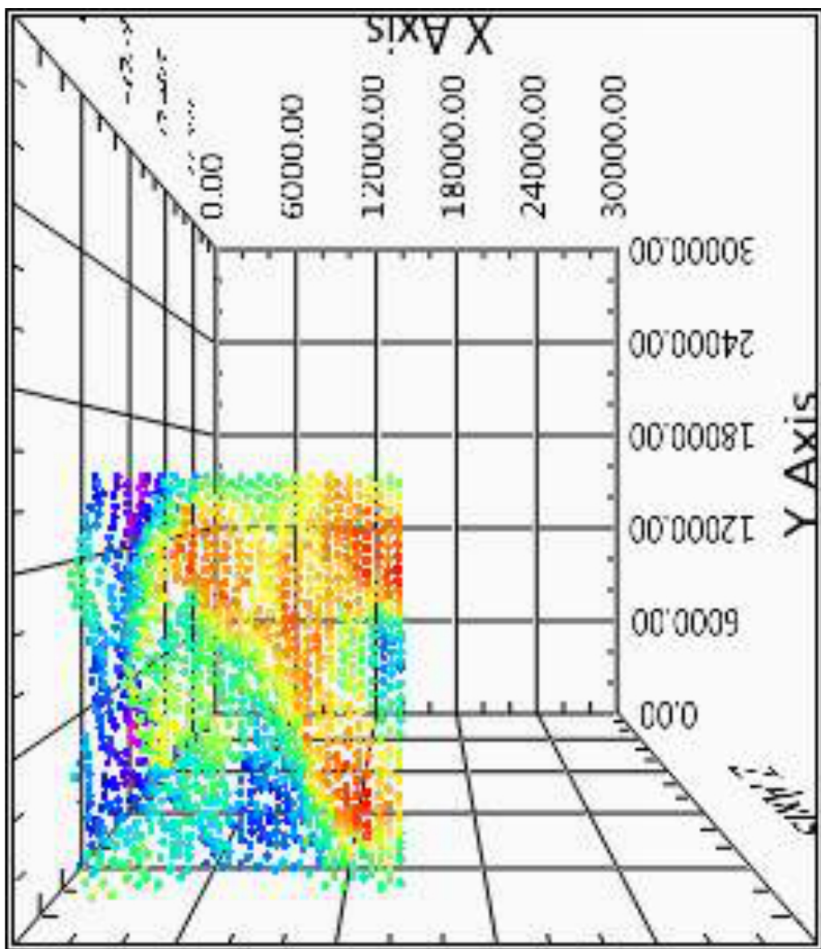








# "Nothing" Scans





# What's Next?

- Determine accurate scale for deflection measurement to actual  $z$  height.
- Try to reduce noise in detector signal
- Reduce reflections
- Focus laser better
- Try better scanning methods than ICM